## Notice of References Cited Application/Control No. 10/593,630 Examiner JOSE M. DIAZ Applicant(s)/Patent Under Reexamination IDE ET AL. Page 1 of 1

## U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-2002/0061418 A1	05-2002	Imanishi, Yasuo	428/690
*	В	US-2003/0127967 A1	07-2003	Tsutsui et al.	313/498
*	С	US-2003/0170491 A1	09-2003	Liao et al.	428/690
*	D	US-2004/0061136 A1	04-2004	Tyan et al.	257/200
	Е	US-			
	F	US-			
	G	US-			
	Ι	US-			
	-	US-			
	7	US-			
	K	US-			
	┙	US-			
	М	US-			

## FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	Ν	JP 2003264085 A	09-2003	Japan	TSUTSUI et al.	H05B 33/14
	0					
	Ρ					
	σ					
	R					
	S					
·	Т					

## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)					
	C						
	V						
	w						
	х						

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.